



FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 2043/US	APPLN. NO. 09/746,618
	APPLICANT: Kenneth R. Wilsher et al.	
	FILING DATE December 21, 2000	GROUP 2877

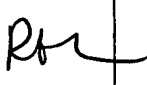
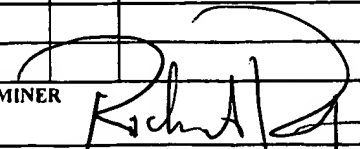
U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
R	160,407	03/1875	Eubank			
R	5,631,571	05/1997	Spaziani et al.	324	752	
R	5,751,159	05/1998	Holm et al.	324	767	
R	6,160,407	12/2000	Nikawa	324	750	

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLISHED DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER 	Valdmanis, J., "Advanced Electro-Optic Sampling Permits Non-Invasive Testing of IC Performance, Electronic Engineering, Morgan-Grampian Ltd., London, GB, Vol. 61, No. 756, pp. 35, 36, 40, 42 (February 1, 1989).
EXAMINER 	DATE CONSIDERED 9 July 2004
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	